

Supplementary Materials for

**“Electrolyte Engineering for the Mass Exfoliation of Graphene Oxide across  
Wide Oxidation Degrees”**

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**This Supplementary Information includes the following sections:**

**Experimental Section/Methods**

**Table S1. The diagram of correspondence between sample labels and electrolyte compositions in the second exfoliation step.**

**S1. Electrolyte concentration-dependent X-ray diffraction (XRD) results and Raman spectra of exfoliated graphite oxides (GOs).**

**S2. The thermogravimetric analysis (TGA) of exfoliated GOs across wide oxidation degrees.**

**S3. The X-ray photoelectron spectroscopy (XPS) spectra for GO samples across wide oxidation degrees.**

**S4. The atomic force microscopy (AFM) height profiles for monolayer GO samples across wide oxidation degrees.**

**S5. The schematic illustration of the fabrication of GO-based composite films.**

**S6. The stress-strain curves for composite films composed of polymer and GO across wide range of oxidation degrees.**

**Table 1. The comparison of measured hole and electron mobility in field-effect transistor devices based on chemical exfoliated GO and rGO.**

**Table 2. The elemental ratios of carbon to oxygen (C/O) of various types of graphene and their respective oxidants, along with the oxidation duration.**

## **Experimental Section/Methods**

**Materials** : Graphite foil (width: 10 cm, thickness: 0.05 mm, purity: 98%) was purchased from SKF (Tianjin) Energy Saving Technology Co., Ltd. Hydrazine sulfate, ammonium sulfate, acrylamide, N,N'-methylenebis(2-propenamide), ammonium persulfate, N,N,N',N'-tetramethylethylenediamine, calcium chloride (CaCl<sub>2</sub>) and sodium alginate (SA) were purchased from Aladdin and used without any additional purification. Polyvinyl alcohol (PVA) was purchased from Sigma-Aldrich and used without further purification. Concentrated sulfuric acid (purity: 95% ~ 98%) was purchased from Jing Chun Chemical Co. Ltd and used without further purification.

### **Electrochemical exfoliation of GO across wide oxidation degrees**

Commercial graphite foils served as the anode (with platinum mesh as the cathode) and were pre-intercalated with concentrated sulfuric acid in an electrochemical cell at a voltage of 2.2 V. Subsequently, the pre-intercalated graphite was transferred to the second cell for exfoliation/oxidation at a voltage of 10 V, containing various electrolytes (hydrazine sulfate: 0.01 M, 0.05 M, 0.1 M, 0.2 M; H<sub>2</sub>SO<sub>4</sub>: 10 wt%, 30 wt%, 50 wt%, 70 wt%; 50 wt% H<sub>2</sub>SO<sub>4</sub> mixed with 0.1 M ammonium sulfate, 0.0001 M KMnO<sub>4</sub>, 0.001 M KMnO<sub>4</sub>, 0.01 M KMnO<sub>4</sub>, and 0.1 M KMnO<sub>4</sub>). It is important to note that EcE-G1 denotes the electrolyte solution composed of 50% H<sub>2</sub>SO<sub>4</sub>-0.01 M hydrazine sulfate used in the second stage. Similarly, EcE-G2, EcE-G3, EcE-G4, EcE-G5, and EcE-G6 represent the electrolyte solutions composed of 50% H<sub>2</sub>SO<sub>4</sub>-0.1 M hydrazine sulfate, 50% H<sub>2</sub>SO<sub>4</sub>-0.001 M KMnO<sub>4</sub>, 50% H<sub>2</sub>SO<sub>4</sub>-0.0001 M KMnO<sub>4</sub>, 50% H<sub>2</sub>SO<sub>4</sub>-0.01 M KMnO<sub>4</sub>, and 50% H<sub>2</sub>SO<sub>4</sub>-0.1 M KMnO<sub>4</sub>, respectively.

**Table S1.** The diagram of correspondence between sample labels and electrolyte compositions in the second exfoliation step.

Types of graphene	Oxidant
EcE-G1	0.01 M Hydrazine sulfate
EcE-G2	0.1 M Ammonium sulfate
EcE-G3	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.001 M KMnO <sub>4</sub>
EcE-G4	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.0001 M KMnO <sub>4</sub>
EcE-G5	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.01 M KMnO <sub>4</sub>
EcE-G6	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.1 M KMnO <sub>4</sub>

### **Preparation of polyacrylamide (PAAm) hydrogels**

A uniform solution phase was prepared by dissolving 15 g of acrylamide, 0.3 g of N,N'-methylenebis(acrylamide), and 0.3 g of ammonium persulfate in 100 mL of distilled water. Subsequently, 300  $\mu$ L N,N,N',N'-tetramethylethylenediamine was added to initiate radical polymerization for 5 minutes at room temperature. The obtained hydrogels were then thoroughly rinsed with abundant water to remove unreacted components and ensure the complete swelling of the hydrogels.

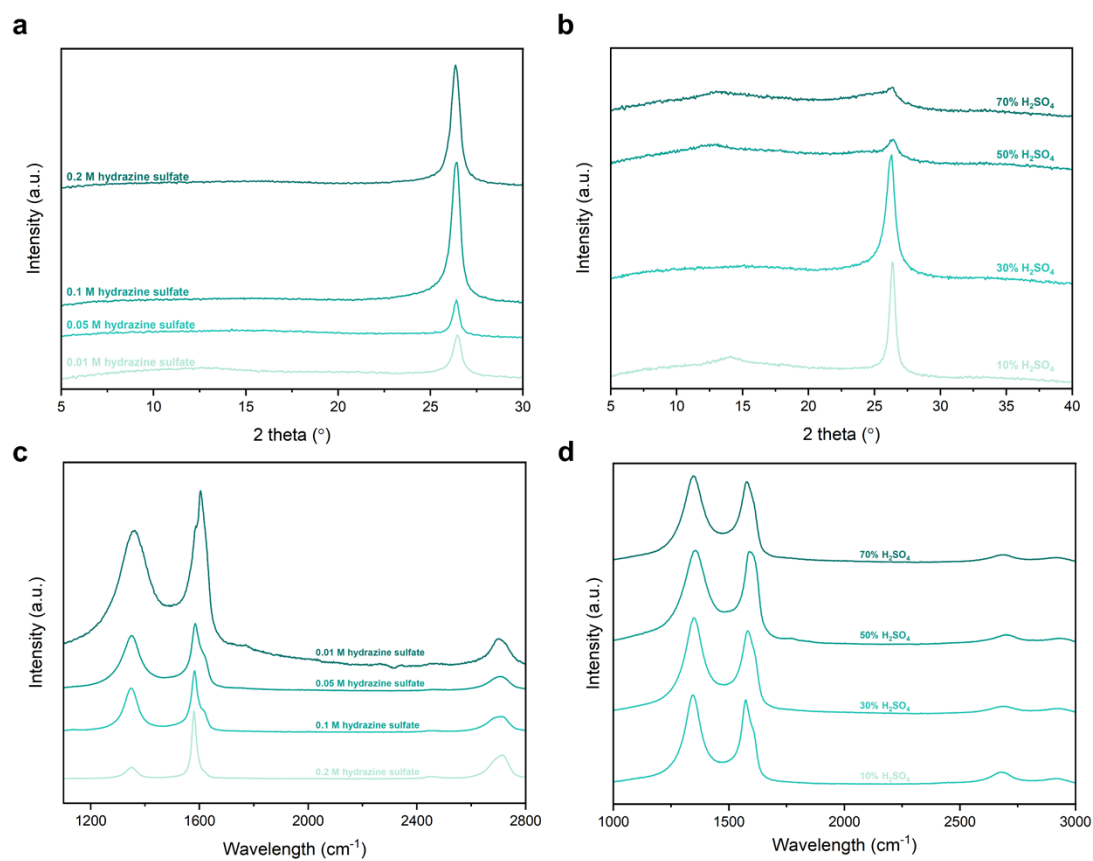
### **Fabrication of GO-based composite films**

Before the fabrication process, the PAAm hydrogels were soaked in deionized water to achieve full swelling. Subsequently, CaCl<sub>2</sub> powder was added to the mixture to form a 0.05 M CaCl<sub>2</sub> solution, facilitating further impregnation of Ca<sup>2+</sup> into the PAAm hydrogels. Additionally, a solution containing PVA, SA, GO, and water was sequentially prepared by sequential addition into a beaker and stirred until homogeneous, with a mass ratio of SA : PVA : GO = 5 : 4 : 1 (referred to as the SA-based solution). During fabrication, an appropriate amount of the SA-based solution was poured onto the

PAAm hydrogel-oil interface. Notably, due to superspreading and the diffusion of  $\text{Ca}^{2+}$  ions from the PAAm hydrogel surface, which facilitated the crosslinking of SA, the SA-based solution rapidly spread between the oil and PAAm hydrogel interface, forming a stable and homogeneous liquid layer. This layer was eventually transformed into a uniform hydrogel film, easily separated from the PAAm hydrogel surface in a water bath. Following this, the composite gel films were dried in an oven at 60 °C and atmospheric pressure for 5 hours, resulting in the collection of uniform and continuous GO-based composite films.

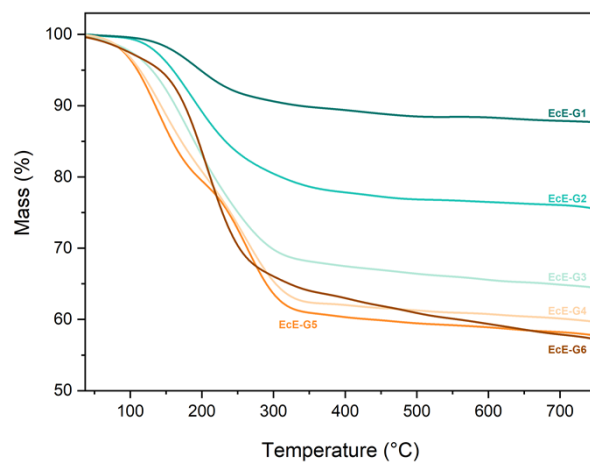
## Characterizations

High-resolution transmission electron microscopy (HRTEM) was conducted using an FEI Titan 80–300 S. Raman spectra were acquired utilizing a LabRAM HR Evolution with a 532 nm laser at ambient conditions. X-ray diffraction (XRD) patterns were collected on Bruker D8 DISCOVER (Cu K $\alpha$  radiation,  $\lambda = 1.54056 \text{ \AA}$ ) at room temperature, with diffraction patterns measured in a  $2\theta$  range of 8–70° at a step speed of 5°/min. X-ray photoelectron spectroscopy (XPS) measurements were conducted with ESCALABXi+ under ultrahigh vacuum conditions. Small-angle X-ray scattering (SAXS) measurements were carried out at Xeuss 3.0 HR using an incident Cu-K $\alpha$  X-ray beam, oriented vertically to the sample plane, with a detector-sample distance of 55 mm. Thermogravimetric analysis (TGA) results were obtained using the STA 449 F5 Jupiter instrument, with a temperature range between room temperature and 800 °C under a nitrogen (N<sub>2</sub>) atmosphere. Atomic force microscopy (AFM) images were obtained in tapping mode using a Bruker Dimension Icon. Mechanical properties were assessed using the ESM303 instrument at a tensile rate of 0.5 mm/min. UV-vis absorption spectra were measured using the SHIMADZU UV-3600 Plus spectrophotometer.

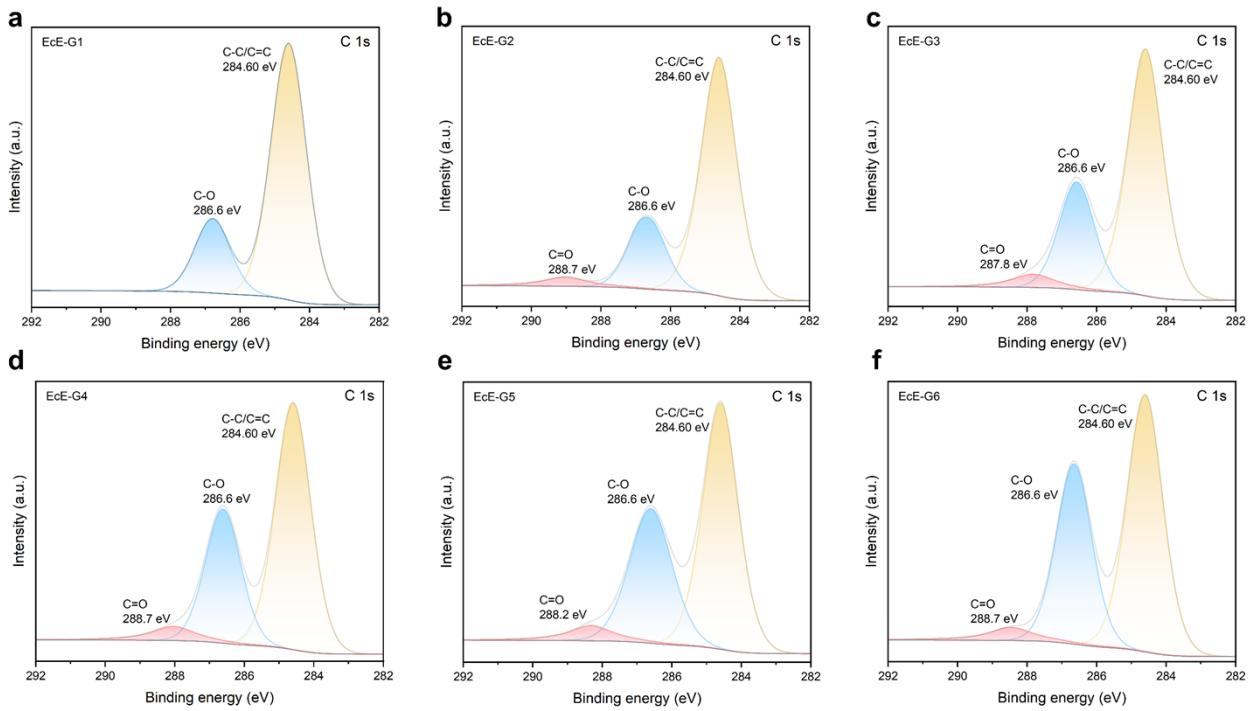


**Supplementary Figure S1. Electrolyte concentration-dependent X-ray diffraction (XRD) results and Raman spectra of exfoliated graphite oxides (GOs).** XRD and Raman spectra of exfoliated GOs in the secondary electrolyte of (a) hydrazine sulfate (0.01 M to 0.2 M), (b) H<sub>2</sub>SO<sub>4</sub> (10 wt% to 70 wt%).

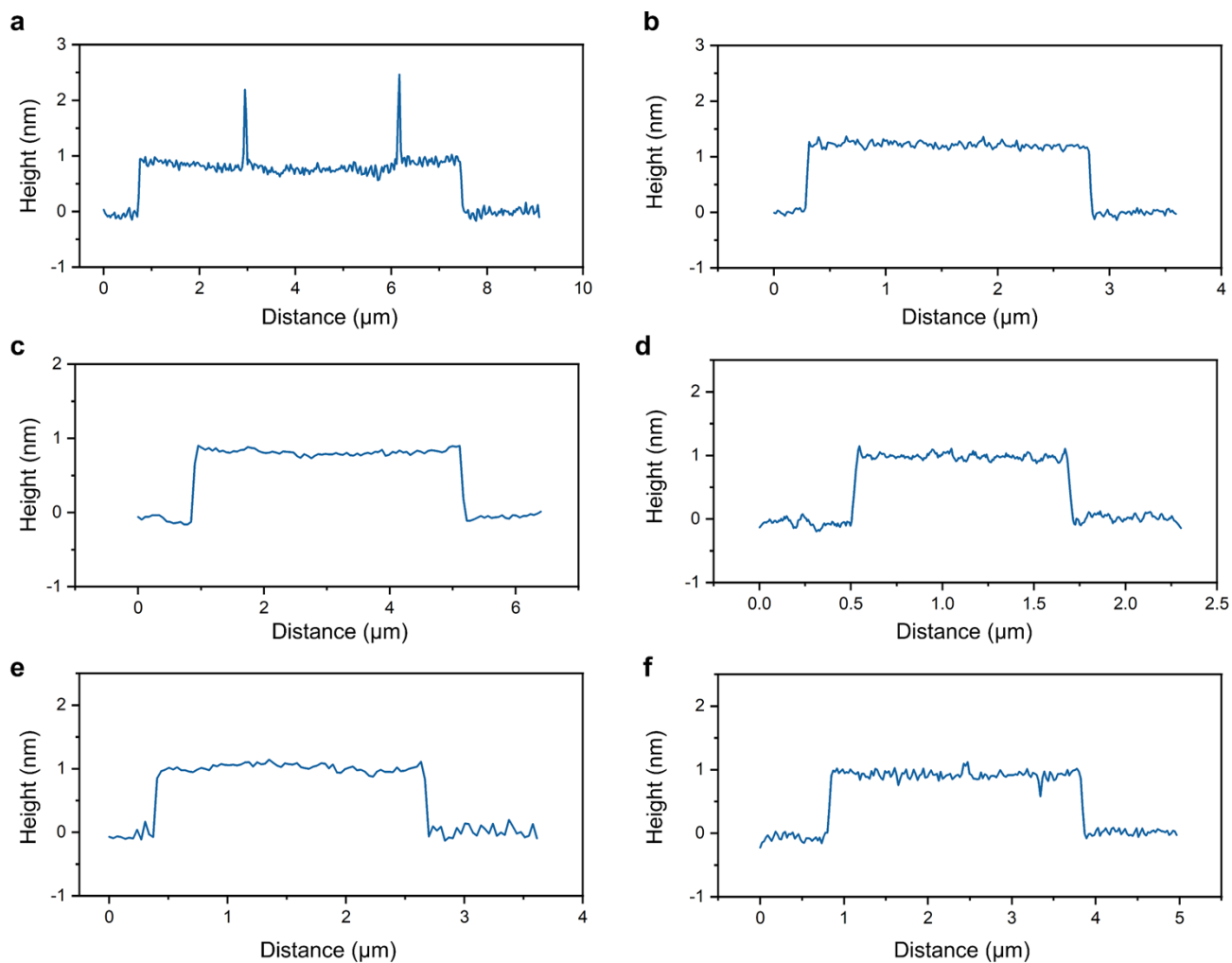




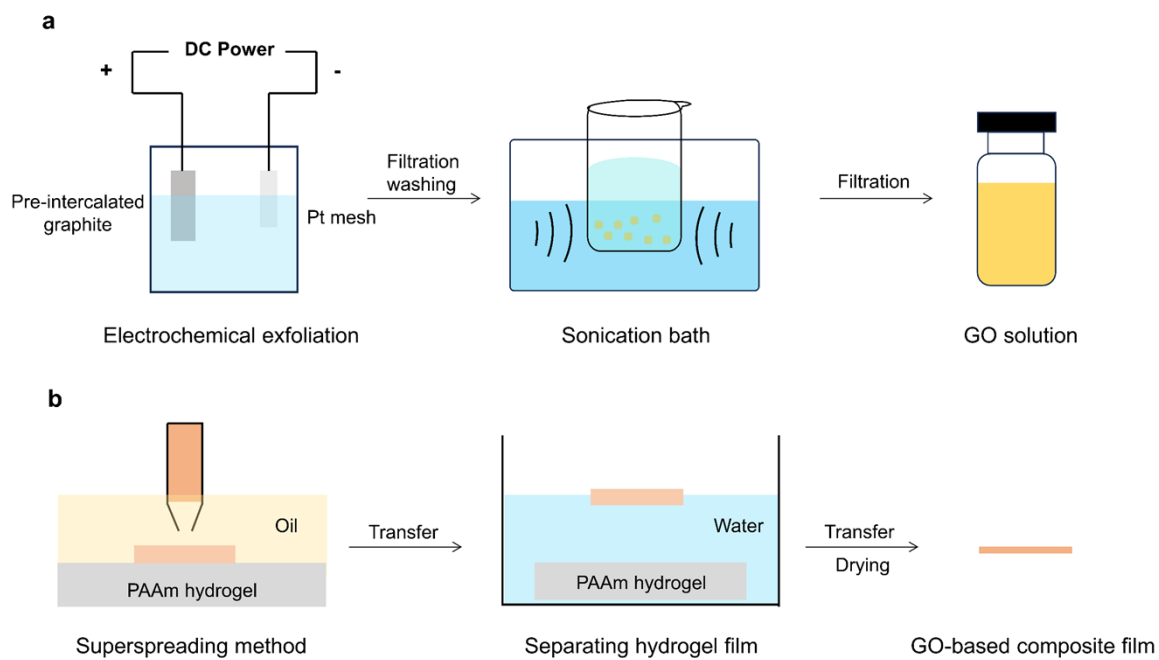
**Supplementary Figure S2. The thermogravimetric analysis (TGA) of exfoliated GOs across wide oxidation degrees.**



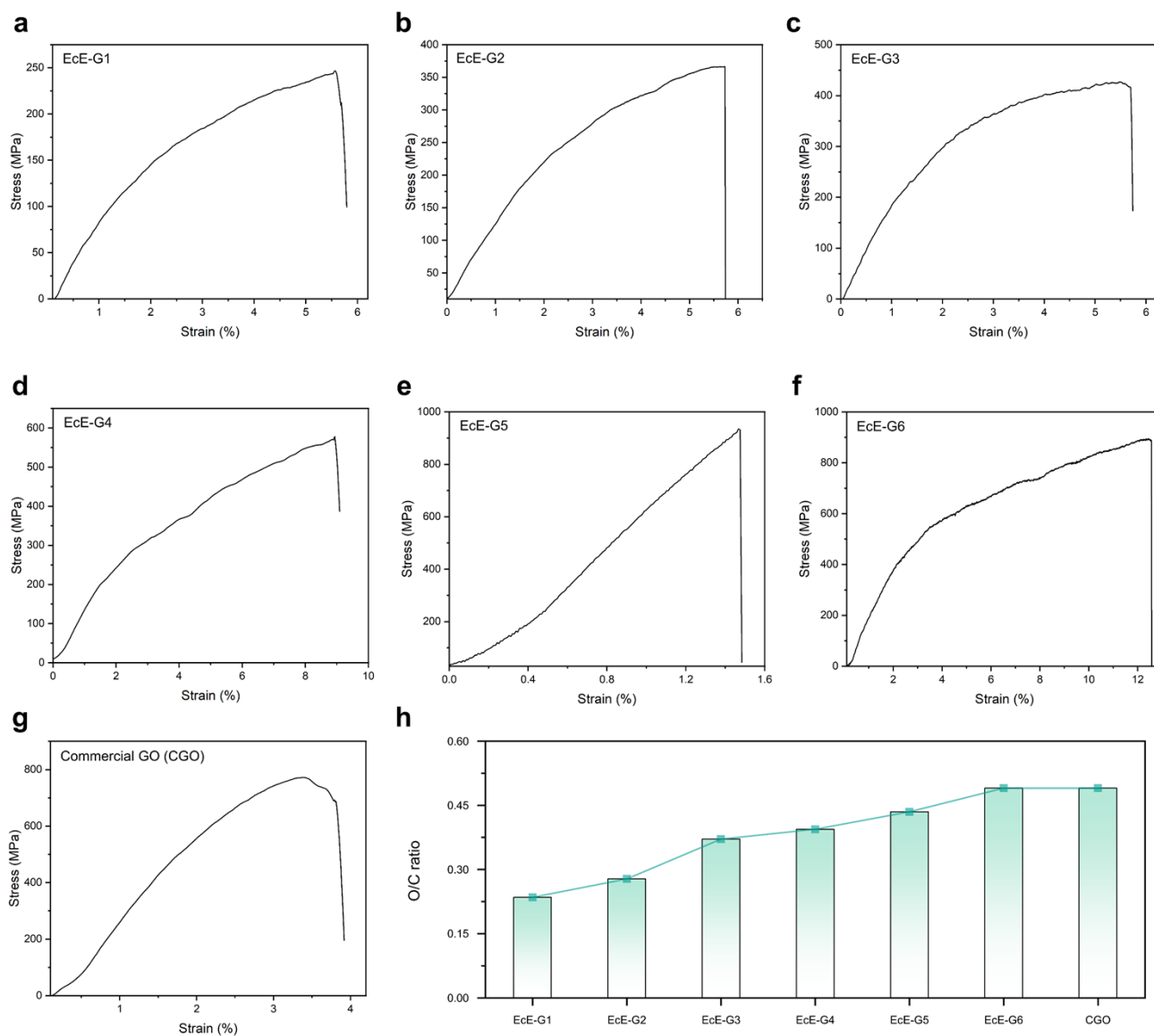
**Supplementary Figure S3. The X-ray photoelectron spectroscopy (XPS) spectra for GO samples across wide oxidation degrees.** Representative XPS spectra of the GOs exfoliated in post-exfoliation electrolytes include: (a) EcE-G1, (b) EcE-G2, (c) EcE-G3, (d) EcE-G4, (e) EcE-G5, and (f) EcE-G6.



**Supplementary Figure S4. The atomic force microscopy (AFM) height profiles for exfoliated GO monolayers across wide oxidation degrees.** The relevant height profiles in Figure 5 (a~f) along the dashed line in each panel are presented, corresponding to (a) EcE-G1, (b) EcE-G2, (c) EcE-G3, (d) EcE-G4, (e) EcE-G5, and (f) EcE-G6.



**Supplementary Figure S5. The schematic illustration of the fabrication of GO-based composite films.** (a) The two-step electrochemical approach for the mass production of GO nanosheets. (b) Preparation of composite films using the superspreading method.



**Supplementary Figure S6. The stress-strain curves for composite films composed of polymer and GO across wide range of oxidation degrees. (a) EcE-G1. (b) EcE-G2. (c) EcE-G3. (d) EcE-G4. (e) EcE-G5. (f) EcE-G6. (g) Commercial GO. (h) The elemental ratios of oxygen to carbon (O/C) of EcE-G1, EcE-G2, EcE-G3, EcE-G4, EcE-G5, EcE-G6, and commercial GO.**

**Table S1.** The comparison of measured hole and electron mobility in field-effect transistor devices based on chemical exfoliated GO and rGO.

Types of Graphene	Number	Chemical treatment	Hole mobility ( $\text{cm}^2 \text{V}^{-1} \text{s}^{-1}$ )	Electron mobility ( $\text{cm}^2 \text{V}^{-1} \text{s}^{-1}$ )	Reference
Graphene Oxide (GO)	1	GO	0.1-1	N.A.	[1]
	2	GO	0.01-10	N.A.	[2]
Reduced Graphene Oxide (rGO)	3	Photo-reduced GO	0.03	0.01	[3]
	4	Thermal (1000 °C)-reduced GO	5.1	1.1	[4]
	5	Reduced GO	0.01-12	N.A.	[5]
	6	Hydrazine-reduced GO	0.25-0.67	N.A.	[6]
	7	Hydrazine-reduced GO	43.6	14.9	[7]
	8	Hydrazine-reduced GO	2-200	0.5-30	[8]
	9	Na-NH <sub>3</sub> -reduced GO	123	N.A.	[9]
	10	Reduced GO	0.05-200	N.A.	[10]
	11	Hydriodic/trifluoroacetic acid-reduced GO	250	200	[11]
	12	Thermal (1000 °C)-reduced GO (multi-layer)	365	281	[4]
Liquid-phase Exfoliated Graphene (LPE-G)	13	LPE-G	95	N.A.	[12]
Electrochemical Exfoliated Graphene	14	Diluted H <sub>2</sub> SO <sub>4</sub> -EcE-G	5.5-17	N.A.	[1]

(EcE-G)	15	$(\text{NH}_4)_2\text{SO}_4\text{-EcE-G}$	310	N.A.	[13]
	16	Radical-assisted-EcE-G	405	N.A.	[14]
	17	Two-step Electrochemical Exfoliated Graphene	562	892	This Work

**Table S2.** The elemental ratios of carbon to oxygen (C/O) of various types of graphene and their respective oxidants, along with the oxidation duration.

Types of graphene	C/O ratio	Oxidant	Data source
EcE-G1	4.26	0.01 M Hydrazine sulfate	This work
EcE-G2	3.60	0.1 M Ammonium sulfate	This work
EcE-G3	2.70	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.001 M KMnO <sub>4</sub>	This work
EcE-G4	2.54	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.0001 M KMnO <sub>4</sub>	This work
EcE-G5	2.30	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.01 M KMnO <sub>4</sub>	This work
EcE-G6	2.04	50 wt% H <sub>2</sub> SO <sub>4</sub> + 0.1 M KMnO <sub>4</sub>	This work
Commercial GO	2.04	Concentrated H <sub>2</sub> SO <sub>4</sub> + 3 g/g KMnO <sub>4</sub> + 5 mL/g H <sub>2</sub> O <sub>2</sub>	[15]
Hofmann's method GO	3.65	Concentrated H <sub>2</sub> SO <sub>4</sub> + 9 mL/g HNO <sub>3</sub> + 11 g/g KClO <sub>3</sub>	[16]
Staudenmaier's method GO	4.00	Concentrated H <sub>2</sub> SO <sub>4</sub> + 9 mL/g fuming HNO <sub>3</sub> + 11 g/g KClO <sub>3</sub>	[16]
Hummers' method GO	2.05-3.30	Concentrated H <sub>2</sub> SO <sub>4</sub> + 6 g/g KMnO <sub>4</sub>	[17]



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